International Standard



INTERNATIONAL ORGANIZATION FOR STANDARDIZATION® MEX AND A POLAN OPPANISALINA DO CTANDAPTUSALUM® ORGANISATION INTERNATIONALE DE NORMALISATION

Information processing – Magnetic disk for data storage devices – 96 000 flux transitions per track, 200 mm (7.9 in) outer diameter, 63,5 mm (2.5 in) inner diameter

Traitement de l'information — Disque magnétique pour unités de stockage des données — 96 000 transitions de flux par piste, diamètre extérieur 200 mm (7,9 in), diamètre intérieur 63,5 mm (2,5 in) PREVIE

First edition - 1985-03-15

(standards.iteh.ai)

<u>ISO 7297:1985</u> https://standards.iteh.ai/catalog/standards/sist/59631b90-8e87-4fd5-b334-7a4697a315fa/iso-7297-1985

Descriptors : data processing, information interchange, data storage devices, magnetic disks, physical properties, magnetic properties, dimensions, tests.

Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work.

Draft International Standards adopted by the technical committees are circulated to the member bodies for approval before their acceptance as International Standards by the ISO Council. They are approved in accordance with ISO procedures requiring at least 75 % approval by the member bodies voting: TANDARD PREVIEW

International Standard ISO 7297 was prepared by Technical Committee ISO/TC 97, Information processing systems.

<u>ISO 7297:1985</u> https://standards.iteh.ai/catalog/standards/sist/59631b90-8e87-4fd5-b334-7a4697a315fa/iso-7297-1985

© International Organization for Standardization, 1985 •

Contents

		Page
1	Scope and field of application	1
2	Reference	1
3	General requirements	1
4	Dimensions	2
5	Physical characteristics	2
iTeh ST	Testing of magnetic characteristics	4
(st	anuards.iteh.ai)	7
8	Track quality tests	
https://standards.iteh?a:	ISO 7297:1985 A Requirements for magnetic surfaces - 4fd5-b334-	8
10	7a <mark>4697a315fa/iso-7297-1985</mark> Defects of the magnetic surfaces	8
An	nexes	
А	Air cleanliness class 100	. 12

iTeh STANDARD PREVIEW (standards itch ai) This page intentionally left blank

<u>ISO 7297:1985</u> https://standards.iteh.ai/catalog/standards/sist/59631b90-8e87-4fd5-b334-7a4697a315fa/iso-7297-1985 Information processing – Magnetic disk for data storage devices – 96 000 flux transitions per track, 200 mm (7.9 in) outer diameter, 63,5 mm (2.5 in) inner diameter

1 Scope and field of application TANDARD NOTER This will usually require the limitation of the allowed ambient field to the range of 300 to 2 000 A/m.

This International Standard specifies the mechanical, physical site and magnetic characteristics of a lubricated magnetic disk of 3.1.1 Operation 3.1.1 Operation diameter intended for mounting in data storage devices 0.7297;1985.

https://standards.iteh.ai/catalog/standards/si The International Standard defines the requirements for a disk to give satisfactory performance at 95 840 flux transitions per track.

When used at other densities, equivalent performance may require changes to the mechanical, magnetic and electrical criteria.

NOTE — The original design of the subject of this International Standard was made using the Imperial measurement system. Some later developments, however, have been made using SI units. In the process of conversion into the alternative system, values may have been rounded. Therefore, the two sets of figures are consistent with, but not exactly equal to, each other. Either set may be used, but the two shall be neither mixed nor reconverted.

2 Reference

ISO 1302, Technical drawings — Method of indicating surface texture on drawings.

3 General requirements

3.1 Operation and storage environment

To prevent corruption of data, the ambient stray magnetic field intensity at the surface of the disk shall not exceed 4 000 A/m. When heads are present, the general ambient field shall be reduced to take account of the concentrating effect of the core of the head.

The operating temperature of the air surrounding the disk shall be within the range 15 to 57 °C (59 to 135 °F) at a relative humidity of 8 to 80 %. The wet bulb temperature shall not exceed 26 °C (79 °F). The air surrounding the disk shall be of cleanliness class 100, as defined in annex A.

3.1.2 Storage

The storage temperature shall be within the range -40 to +65 °C (-40 to +150 °F) at a relative humidity of 8 to 80 %. The wet bulb temperature shall not exceed 30 °C (86 °F). Under no circumstances shall condensation on the disk be allowed to occur.

Storage under the extreme conditions of the above range is not recommended. A temperature gradient of more than 10 °C (18 °F) per hour should be avoided.

3.2 Test conditions

Unless otherwise stated, measurements shall be carried out at 23 \pm 3 °C (73 \pm 5 °F), 40 to 60 % relative humidity after a period of acclimatization during which condensation on the disk shall not be allowed to occur. Tests requiring the use of heads shall be performed in air of cleanliness class 100.

3.3 Material

The disk may be constructed from any suitable material so long as the dimensional, inertial and other functional requirements of this International Standard are maintained.

3.4 Coefficient of thermal expansion

The coefficient of thermal expansion of the disk material shall be

$$\frac{\Delta L}{L \Delta t} = \frac{1}{L} \times \frac{L_{57} - L_{15}}{42} \,\mathrm{K}^{-1} = (24 \pm 1) \times 10^{-6} \,\mathrm{K}^{-1}$$
$$\left[\frac{\Delta L}{L \Delta t} = \frac{1}{L} \times \frac{L_{135} - L_{59}}{76} \,\mathrm{per}^{\,\mathrm{o}}\mathrm{F} = (13.3 \pm 0.5) \times 10^{-6} \,\mathrm{per}^{\,\mathrm{o}}\mathrm{F}\right]$$

The sample length L is equal to

$$\frac{L_{57} + L_{15}}{2} \left(\frac{L_{135} + L_{59}}{2} \right)$$

where L_{57} (L_{135}) and L_{15} (L_{59}) are the lengths at 57 °C (135 °F) and 15 °C (59 °F), respectively.

3.5 Surface identification

The direction of relative motion between head and disk shall be consistent. The disk surface that is to rotate counter-clockwise shall be identified.

iTeh STANDARD PREVI

4 **Dimensions** (see figures 1 to 3)

For measurement of the radii indicated hereafter, the disk shall be mounted on a reference hub (see figure 1) having $\underline{13}_{O}$ 7297:198 \gg 38,6 mm (1.52 in) diameter, measured at 23,0 ± 0,5 °C (73 ± 1 °F) of variable of the average of the second standards site have a standard s

$$d_1 = 63,475 \stackrel{0}{_{-0.010}} \text{mm} (2.499 \ 0 \stackrel{0}{_{-0.0004}} \text{in})$$

and an outer radius

$$r_1 = 38,10 + 0,10 \text{ mm} (1.500 + 0.004 \text{ in})$$

All radii are referred to the axis of symmetry of this reference hub. The cylindrical surface of the reference hub defined by d_1 shall be contained between two coaxial cylindrical surfaces 10 µm (0.000 4 in) apart.

4.1 Inner diameter

The inner diameter of the disk, measured at 23,0 \pm 0,5 °C (73 \pm 1 °F), shall be

$$d_2 = 63,500 + {0,051 \atop 0} \text{ mm} (2.500 \ 0 + {0.002 \atop 0} \text{ in})$$

The circumference of the inner edge shall be contained between two concentric circles 25 μm (1 000 $\mu in)$ apart.

4.2 Outer diameter

The outer diameter of the disk shall be

 $d_3 = 200,00 \pm 0,10 \text{ mm} (7.874 \pm 0.004 \text{ in})$

The circumference of the outer edge shall be contained between two concentric circles 25 μ m (1 000 μ in) apart.

4.3 Concentricity

The centre of the circumference of the outer edge of the disk shall be contained in a circle of diameter 50 μ m (0.002 0 in) concentric with the centre of the circumference of the inner edge.

4.4 Thickness

The thickness of the disk shall be

 $e = 1,905 \pm 0,025 \text{ mm} (0.075 \pm 0.001 \text{ in})$

4.5 Edge chamfer (see figure 3)

For a distance

/ ≤ 0,76 mm (0.030 in)

from the edges of the disk, the disk contour shall be relieved within the extended boundaries of the disk surfaces. In order to avoid unbalance, the chamfer shall be uniform at all points on the circumference.

4.6 Clamping area

On both sides of the disk, the clamping area shall be an area (standard free of magnetic coating, limited by the inner edge and a radius r_2 :

 $7a4697a315fa/Between r_{2}and the start of the chamfer, the variation of the disk thickness shall not exceed 7,5 µm (300 µin).$

4.7 Location of magnetic surfaces

On both sides of the disk, the area of magnetic surface over which heads may fly shall extend from an inside radius r_3 to an outside radius r_4 :

 $r_3 \leq 41,7 \text{ mm} (1.64 \text{ in})$

 $r_4 \ge 97,0 \text{ mm} (3.82 \text{ in})$

5 Physical characteristics

5.1 Moment of inertia

The moment of inertia of the disk shall not exceed

1,0 g·m² (3.4 lb·in²)

5.2 Maximum rotational frequency

The disk shall be capable of withstanding the effect of stress at a rotational frequency of 7 000 r/min.

5.3 Runout

For measuring the axial runout and the velocity and the acceleration of axial runout, the disk shall be clamped and driven according to 5.3.1.

The requirements of 5.3.2, 5.3.3 and 5.3.4 shall be met at all radii between r_3 and r_4 .

5.3.1 Test spindle requirements and clamping conditions (see figure 1)

The disk shall be clamped on the reference hub by a force

 $F = 1\ 100\ \pm\ 110\ N\ (250\ \pm\ 25\ lbf)$

evenly applied over an annular surface on the disk defined by

 $r_5 = 34,0 \text{ mm} (1.34 \text{ in})$

 $r_6 = 38,1 \text{ mm} (1.50 \text{ in})$

The finish of the surface of the reference hub on which the disk rests shall be of class N 5 [maximum arithmetical deviation $0,4 \mu m$ (16 μ in)] as defined in ISO 1302.

At any rotational frequency up to 4 000 r/min, the axial runout of the reference hub shall not exceed 1,0 μ m (40 μ in).

5.3.2 Axial runout

iTeh STANDARD PREVIEW 5.5 Cleaning of the magnetic surfaces

The axial runout at any rotational frequency up to 4 000 r/min shall not exceed 0,076 mm (0.003 in), total indicator reading.

Moreover, every point of each surface of the disk shall be 97:1985 located between two planes perpendicular to the axis of the ads o

clamping plane of the respective disk surface.

5.3.3 Velocity of axial runout

With the disk revolving at 3 600 \pm 36 r/min, the velocity of axial runout of the recording disk surfaces shall not exceed 31 mm/s (1.22 in/s). It shall be measured within the band width defined by a low-pass filter with a cut-off frequency of 3 kHz and a high frequency roll-off of 18 dB/octave. The probe diameter shall be 1,7 mm (0.067 in).

5.3.4 Acceleration of axial runout

With the disk revolving at 3 600 \pm 36 r/min, the acceleration of axial runout shall not exceed 38,1 m/s² (1 500 in/s²) within the measurement band-width defined by a low-pass filter with a cut-off frequency of 7 kHz and a high frequency roll-off of 18 dB/octave. The probe diameter shall be 1,7 mm (0.067 in).

5.3.5 Radial runout

The radial runout of the disk depends on the concentricity (see 4.3) and circularity (see 4.1 and 4.2) of the inner and outer edges, as well as on the clamping conditions in the device in which it is mounted. It is therefore not specified by this International Standard.

5.4 Surface roughness

5.4.1 Magnetic surfaces

The finished magnetic surfaces shall have a surface roughness of less than 0,025 μ m (1.0 μ in), arithmetic average, with a maximum deviation in height of 0,25 μ m (10 μ in) from the average, when measured with a stylus of radius 2,5 μ m (100 μ in) with a 0,5 mN load, and a 750 μ m (0.03 in) upper cutoff range.

The finished magnetic surfaces shall have an undulation profile with a peak-to-peak amplitude of less than 0,15 μ m (6.0 μ in) when measured over a radial length of 4,8 mm (0.19 in) with a stylus of radius 2,5 μ m (100 μ in) with a 0,5 mN load and a lower cut-off range of 250 μ m (0.01 in).

5.4.2 Clamping area

The finished surface of the clamping area shall have a surface roughness of less than 0,8 μ m (30 μ in), arithmetic average, with a maximum deviation in height of 2,0 μ m (80 μ in) from the average, when measured with a stylus of radius 2,5 μ m (100 μ in) with a 0,5 mN load, and a 750 μ m (0.03 in) upper cutoff range.

297-1985 The disk shall be able to withstand the effect of 10 000 head take-off and landing operations on any part of the disk surfaces between r_3 and r_4 .

Measurements shall be taken as follows :

5.6.1 Head conditioning

Condition the head (of type specified in 6.4) by 50 take-off and landing operations outside the test area defined in 5.6.2. All write operations on a track shall be preceded by DC-erasure (see 6.5.2) of that track.

5.6.2 Read amplitude

Select two reference tracks, A and B, 12,7 mm (0.50 in) apart. Write at 2f (see 6.9) on these two tracks and on at least 20 test tracks evenly spaced between A and B. Measure the read amplitude on each track before moving the head to the next track. The average read signal from the two reference tracks before the wear test shall be

$$E_{\rm AV} = \frac{E_{\rm A} + E_{\rm B}}{2}$$

5.6.3 Wear test

Locate the head between tracks A and B so that no part of the head touches an area which would be flown over when the pole tip of the head is on either track A or track B. Without moving the head, perform 10 000 take-off and landing operations, during which the disk shall be accelerated and decelerated between 0 and 3 600 r/min. Acceleration and deceleration time between 0 and 2 400 r/min shall be within 6,0 ± 1,0 s.

5.6.4 Head wear factor

Repeat the procedure given in 5.6.2 using the same tracks. The average read signal from the two reference tracks after the wear test shall be

$$E'_{\rm AV} = \frac{E'_{\rm A} + E'_{\rm B}}{2}$$

The head wear factor is defined as

$$\frac{E_{\rm AV}}{E'_{\rm AV}}$$

Multiply the second set of readings for the test tracks by this head wear factor.

5.6.5 Durability criteria

The following requirements shall be net eh STANDA described in annex C. F.

(standarce 2.21 Track Spacing the head wear factor shall be \leq 1,11; a)

for each of the test tracks the corrected reading derived For testing purposes, the track centreline spacing shall be such b) in 5.6.4 shall not differ by more than 10 % from the reading that the whole area defined in 6.2.3 will be tested. https://standards.iteh.ai/catalog/standards taken in 5.6.2.

7a4697a315fa/isc

5.7 Head/disk gliding requirements

The magnetic surface shall be free of surface defects which would cause head to disk contact when the head is flying at 0,35 μ m min. (14 μ in min.) at radius r_3 , and proportionally increasing in flying height to 0,43 μm min. (17 μin min.) at radius r_4 .

Dynamic head/disk friction 5.8

In the area between radii r_3 and r_4 , the average dynamic coefficient of friction μ_1 shall not be greater than 0,200. Its peak-topeak variation $\Delta \mu_1$ shall not exceed 0,035.

The method of measuring is described in annex B.

5.9 Static head/disk friction

In the area between radii r_3 and r_4 , the static coefficient of friction μ_2 , when measured after the head has been in stationary contact with the disk under the conditions of 3.1.1 for at least 48 h, shall not be greater than 1,0.

The method of measurement is described in annex B.

5.10 Discharge path

The disk shall allow flow of electrical charges from the magnetic surface to the clamping area.

Testing of magnetic characteristics 6

6.1 General conditions

6.1.1 Rotational frequency

The rotational frequency shall be 3 600 \pm 36 r/min in any test period.

6.1.2 Ambient stray magnetic field

The intensity of the ambient stray magnetic field shall not exceed 300 A/m.

6.2 Track and recording conditions

6.2.1 Width of tracks

For testing purposes, the effective track width shall be

40 ± 4 μm (1 600 ± 160 μin)

A suggested method of measuring the effective track width is

7297-1985 6.2.3 Tested area

All functional tests and all track quality tests shall be performed between an innermost track having its centreline at a radius r_7 and an outermost track having its centreline at a radius r_8 :

$$r_7 = 56,5 \text{ mm} (2.22 \text{ in})$$

 $r_8 = 91,7 \text{ mm} (3.61 \text{ in})$

6.2.4 Location of the line of access

The line of access shall be radial within 0,25 mm (0.010 in).

6.2.5 Recording offset angle

At the instant of writing or reading a magnetic transition, the transition may have an angle of 60' maximum with the line of access.

Standard reference surface 6.3

6.3.1 Characteristics

The standard reference surface shall be characterized at the innermost and outermost tracks (radii r_7 and r_8) using a test head specified in 6.4 having its calibration factors (see 6.4.9) equal to 1.

When recorded at 1f (see 6.9) using this test head, the track average amplitude (see 6.8) shall be

0,72 mV at radius r7

1,38 mV at radius r₈

When recorded at 2f (see 6.9) using this test head, the track average amplitude (see 6.8) shall be

0,54 mV at radius r7

1,20 mV at radius r_a

When measured at radius r₈ using this test head, the overwrite ratio (see 7.3) shall be 0,022.

6.3.2 Secondary standard reference surface

This is a surface the output of which shall be related to the standard reference surface via calibration factors C_{D1} (for 1*f*), C_{D2} (for 2*f*) and an overwrite calibration factor C_{D0} .

The amplitude calibration factors $C_{\rm D}$ are defined by

6.4.6 Resonant frequency $C_{\rm D} = \frac{\text{Standard reference surface output}}{\text{Secondary standard reference surface output}}$

The resonant frequency of the total read/write coil of the head shall be such as to meet the requirements given in 6.6.1.

For both C_{D1} and C_{D2} the measurements shall be made at radii r_7 and r_8 . ISO 7297:196,4.7 Resolution

https://standards.iteh.ai/catalog/standards/sist/59631b90-8e87-4fd5-b334-The overwrite calibration factor C_{D0} is defined by 7a4697a315fa/iso-72b9-1985 bead shall have a reso The test head shall have a resolution of (74 \pm 3) % at radius r_7

Overwrite ratio of standard reference surface $C_{D0} =$ Overwrite ratio of secondary standard reference surface

The measurements shall be made at radius r_8 .

To qualify as a secondary standard reference surface, the calibration factors $C_{\rm D}$ and $C_{\rm D0}$ for such disks shall satisfy $0,90 \leq C_{\rm D} \leq 1,10$ at the measured radii for both frequencies.

NOTE - It is expected that a standard reference surface for signal amplitude will be established by the Physikalisch-Technische Bundesanstalt (PTB), Lab. 5.11, D-3300 Braunschweig, Germany F. R. Secondary signal amplitude reference surfaces or a calibration service would then also be made available.

6.4 Test head

The test head shall be calibrated to the standard reference surface, and used for amplitude measurements and testing of the magnetic surfaces.

NOTE - A suitable test head is a 3350-type head without amplifier, modified to conform to the requirements listed hereunder.

6.4.1 Gap width

The width of the recording gap (measured optically) shall be

$$37 \pm 4 \,\mu m (1 \, 450 \pm 150 \,\mu in)$$

6.4.2 Gap length

The length of the recording gap shall be

1,4 \pm 0,2 μm (55 \pm 8 $\mu in)$

6.4.3 Gap offset angle

The angle between the recording gap in the ferrite core and the relevant mounting surface of the head may be 60' maximum.

6.4.4 Flying height

When flying over the innermost track, the test head shall have a flying height at the gap of

 $0,48 \pm 0,05 \ \mu m \ (19 \pm 2 \ \mu in).$

6.4.5 Inductance

The total head inductance shall be 8,5 \pm 0,5 μH measured in air at 1 MHz. Each leg shall have an inductance of $2,5 \pm 0,3 \mu H.$

and (87 ± 5) % at radius r_8 . Resolution being defined as :

2*f* Amplitude _____ 100 % 1 f Amplitude

6.4.8 Head loading force

The net head loading force shall be such as to achieve the flying height (see 6.4.4) and shall be

 $0,093 \pm 0,010$ N (0.020 9 ± 0.002 2 lbf)

6.4.9 Calibration factors

The amplitude calibration factors of the test head $C_{\rm H1}$ at 1f and C_{H2} at 2*f*, and its overwrite calibration factor C_{H0} shall satisfy $0,90 \le C_{\rm Hi} \le 1,10.$

 $C_{\rm Hi}$ is defined by

$$C_{\text{Hi}} = \frac{\text{Standard reference surface output}}{\text{Actual head voltage measured}}$$

when measured on a standard reference surface, or by

$$C_{\text{Hi}} = \frac{\text{Standard reference surface output}}{(\text{Actual head voltage measured}) \times C_{\text{D}}}$$

when measured on a secondary standard reference surface.

 $C_{\rm H0}$ is defined by

$$C_{\rm H0} = \frac{\rm Standard\ reference\ surface\ overwrite\ ratio}{\rm Actual\ measured\ overwrite\ ratio}$$

when measured on a standard reference surface, or by

$$C_{\rm H0} = \frac{\text{Standard reference surface overwrite ratio}}{(\text{Actual measured overwrite ratio}) \times C_{\rm D0}}$$

when measured on a secondary standard reference surface.

6.5 Conditions for test head measurements

6.5.1 Write current

The 1f write current shall conform to figure 4. The current amplitude measured at the head termination connector shall have two values as shown in table 1.

Ra	ıdii	Write current $(I_{W+} + I_{W-})$	
mm	in	mA tolerance, %	h
91,7 to 74,1	3.61 to 2.92		μ
74,1 to 56,5	2.92 to 2.22	⁷⁰ (st [±] a ¹ nc	la

The differences between the positive and negative amplitudes of the quiescent write current $I_{W_{+}} - I_{W_{-}}$ shall be less than 2 mA The AGC-amplifier shall produce an output voltage V. oc con-2 mA. 7a4697a31

$$T_{\rm R} = 55 \pm 5 \, {\rm ns}$$

 $T_{\rm F} = 55 \pm 5 \, {\rm ns}$

Overshoot : (2,5 \pm 0,5) % of I_W , where $I_W = I_{W+} + I_{W-}$

Two consecutive half periods T_1 , T_2 shall not differ from $\frac{T_1 + T_2}{2}$ by more than 1 %.

6.5.2 DC-erase current

The DC-erase current supplied to one of the two read/write coils when DC-erase is specified shall be as shown in table 2.

Ta	L	-	2
Ia	b	e.	~

Radii		Write	e current
mm	in	mA	tolerance, %
91,7 to 74,1	3.61 to 2.92	40	± 1
74,1 to 56,5	2.92 to 2.22	35	± 1

6.6 Read channel

6.6.1 Input impedance

The differential input impedance of the read channel shall be 750 \pm 37 Ω in parallel with 12 \pm 2,5 pF, including the amplifier input impedance and all other distributed and lumped impedance measured at the input connections of the read amplifier.

The resonant frequency of the electrical circuit comprising the head winding, the input impedance of the read channel and interconnecting wiring shall be 13,0 \pm 0,3 MHz.

6.6.2 Frequency and phase characteristics

The frequency response shall be flat within \pm 0,20 dB from 0,09 MHz to 5,75 MHz (0,06 f to 4 f).

The -3 dB roll-off point shall be at 8,60 MHz (6,*f*).

The attenuation above 8,60 MHz shall not be less than that given by a line drawn through zero dB at 8,60 MHz with a slope of 18 dB/octave.

The phase shift shall be linear within \pm 5° between 0,09 MHz and 5,75 MHz (0,06f and 4f).

6.6.3 Transfer characteristics

For inputs between 0,1 mV peak-to-peak and 3 mV peak-topeak the transfer characteristic of the read channel shall be linear within \pm 3 %, or 15 μ V, whichever is larger. rds.iteh.ai)

6.7 Automatic gain controlled amplifier

$$\begin{array}{l} \text{matrix} \text{start within \pm1 % for input voltages from $V_{\text{in min.}}$ = 0,1 mV\\ \text{peak-to-peak to $V_{\text{in more}}$ = 3 mV peak-to-peak (see figure 5). \end{array}$$

The AGC response time ($T_{\rm R}$) shall be 10 \pm 1 μ s to recover 90 % of the nominal AGC signal output amplitude ($V_{\rm out}$) when the input signal ($V_{\rm in}$) is subjected to a 50 % amplitude step reduction.

All frequencies below 10 kHz shall be attenuated at a rate of 6 dB/octave.

6.8 Track average amplitude, V_{TA}

The track average amplitude, V_{TA} , is the average of the peakto-peak values of the signals over one revolution of the disk, measured at the output of the test head when electrically loaded as described in 6.6.

6.9 Test signals

The recording frequencies specified as 1f and 2f shall be

 $1f = (2\ 875\ \pm\ 3)\ \times\ 10^3\ transitions/s$

 $2f = (5750 \pm 6) \times 10^3$ transitions/s.

6.10 DC-erasure

Unless otherwise specified, all write operations shall be preceded by a DC-erase operation.

Table 1				
Radii		Write current $(I_{W+} + I_{W-})$		
mm	in	mA	tolerance	
1,7 to 74,1	3.61 to 2.92	- 80	DIA	

7 Surface tests

7.1 Amplitude test

7.1.1 Procedure

Write on any part of the surface at 2f, read back and measure the V_{TA} .

7.1.2 Result

The upper limit for the track average amplitude of the corrected test head output shall be 0,70 mV peak-to-peak at radius r_7 and shall increase linearly to a value of 1,56 mV peak-to-peak at radius r_8 . The lower limit for the track average amplitude shall be 0,38 mV peak-to-peak at radius r_7 and shall increase linearly to a value of 0,84 mV peak-to-peak at radius r_8 (see figure 6).

7.2 Resolution test

7.2.1 Procedure

On any part of the magnetic surfaces write at 1*f*, read back and

measure the V_{TA} . Then DC-erase, write at the same position at **S**. **18.1** Positive modulation test 2*f*, read back and again measure the V_{TA} . The values of the measured V_{TA} shall be corrected by the appropriate head calibration factors (see 6.4.9). ISO 7297:1985 https://standards.iteh.ai/catalog/standards/sist/Write on any track at 2*f*, read back and measure the V_{TA} . With

7.2.2 Result

In all cases the ratio

Corrected average track amplitude of 2f-signal

Corrected average track amplitude of 1*f*-signal

shall be 0,80 \pm 0,13.

7.3 Overwrite test

7.3.1 Procedure

Write at 1f at radius r_8 and measure the average amplitude of the 1f-signal with a frequency-selective voltmeter. Without DC-erase, overwrite once at 2f, measure the average amplitude of the residual 1f-signal with the frequency-selective voltmeter.

7.3.2 Result

In all cases the ratio

Average amplitude of 1*f*-signal after overwrite $\times C_{H0}$

Average amplitude of 1*f*-signal before overwrite

shall be less than 0,028.

Track at 27, read back and measure the V_{TA} . With 7a4697a315fa/iso-729a delay of $t_d = 1,55 \pm 0,15 \ \mu s$ after detecting a read pulse exceeding 125 % of 0,5 V_{TA} , count all further such read pulses during a time period $t_{pm} = 3,10 \pm 0,15 \ \mu s$ (see figure 7).

DC-erase a 5-track band with the central track at radius r_7 . Write at radius r_7 at 2*f*, read back and measure the RMS value

 $(V_{\rm BMS})$, using a true RMS-voltmeter with a band width of

Then DC-erase at least five times, read back and measure the RMS value (V_{DCRMS}), unload the head and measure the RMS value of the noise due to all other noise sources (V_{NRMS}).

 $V_{\rm NRMS}$ shall not be greater than 0,025 $V_{\rm RMS}$.

8.1.2 Result

7.4 Residual noise test

10 MHz at the -6 dB point.

 $\sqrt{V^2}_{\text{DCRMS}} - V^2_{\text{NRMS}}$

V_{RMS}

shall be less than 0,05.

7.4.1 Procedure

7.4.2 Result

The ratio

Positive amplitude modulation occurs if the number of the counted pulses exceeds 14.

8.2 Negative modulation test

8.2.1 Procedure

Write on any track at 2*f*, read back and measure the V_{TA} . With a delay of $t_d = 1,55 \pm 0,15 \,\mu s$ after detecting a read pulse not reaching 75 % of 0,5 V_{TA} , count all further such read pulses during a time period $t_{nm} = 60 \pm 1 \,\mu s$ (see figure 7).

8.2.2 Result

Negative amplitude modulation occurs if the number of counted pulses exceeds 230.

8.3 Missing pulse test

8.3.1 Procedure

Write on each track at 2/ and read back using the AGC-amplifier.